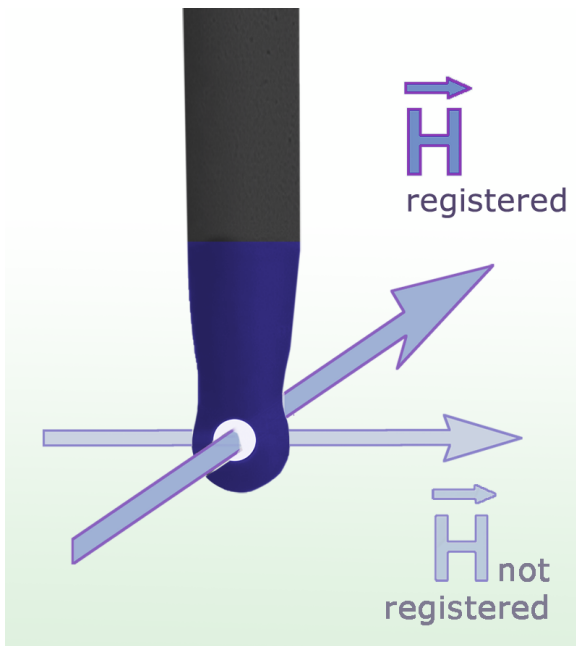


LF-R 3

磁场探头 (100KHz-50MHz)



Short description

LF-R 3型近场探头用于直接在组装件上高分辨率测量射频磁场，例如在引脚和集成电路封装区、导线、旁路电容器和电磁兼容性（EMC）元件。

The LF-R 3 probe is a passive near-field probe. It has the same basic construction as the LF-R 50 and LF-R 400 probes. Of these three probes, the LF-R 3 has the highest resolution. This probe is suitable for measurements close to the components in the high magnetic field strength range, but should not be used for measurements from a distance.

This can be done using LF-R 400 and LF-R 50.

The near-field probe is small and handy. It has a current attenuating sheath and, therefore, is electrically shielded. It can be connected to a spectrum analyzer or an oscilloscope with a 50 Ω input. The H-field probe does not have an internal terminating resistance of 50 Ω .

Technical parameters

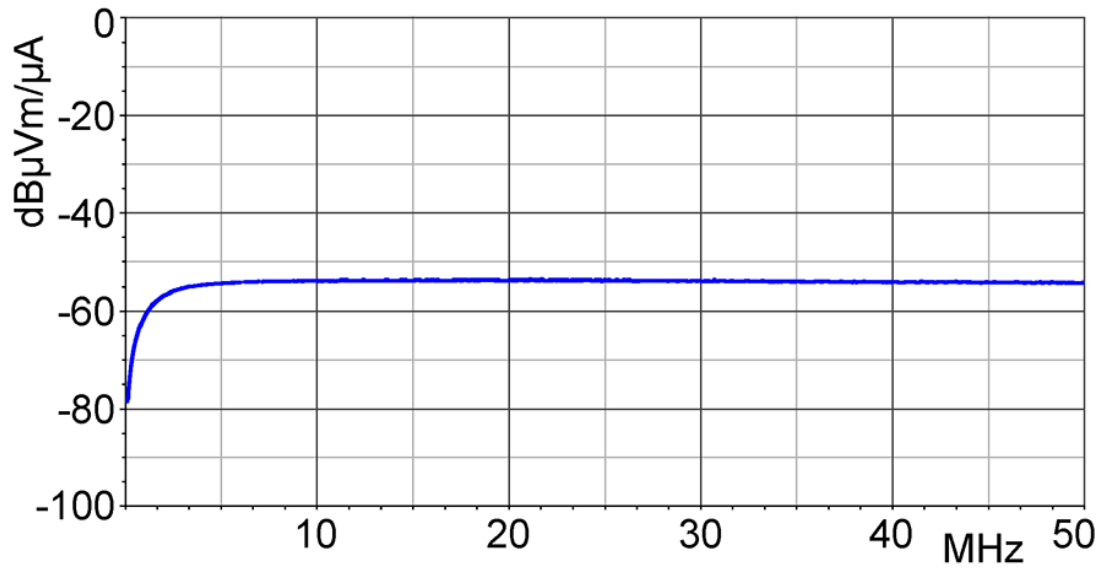
频率范围	100 kHz ... 50 MHz
分辨率	≈ 1 mm
探头尺寸	$\varnothing \approx 3$ mm
输出接口	SMB, male, jack

LF-R 3

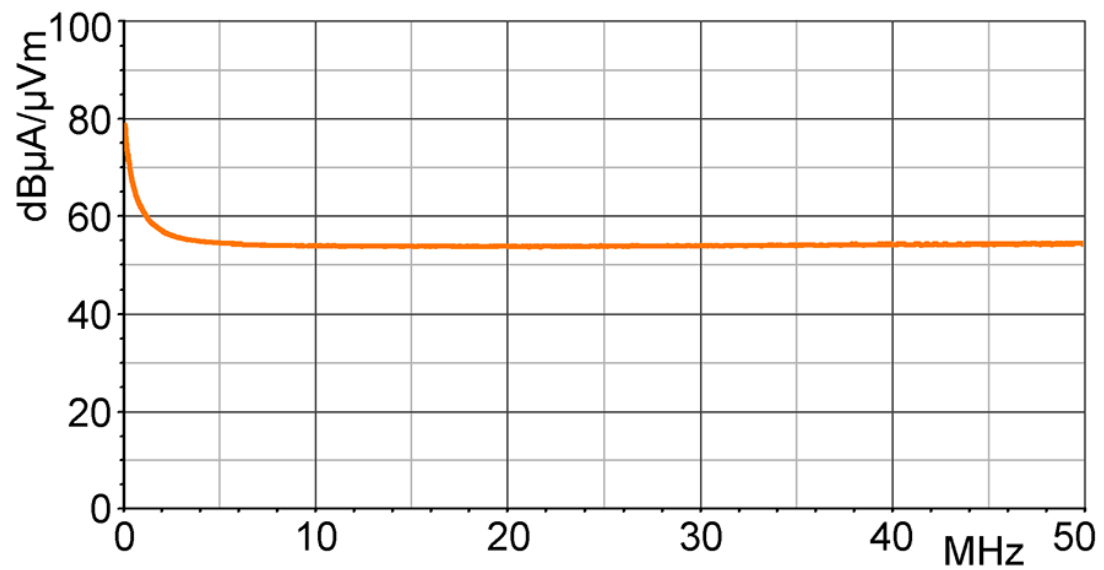
磁场探头 (100KHz-50MHz)

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频率特性 [dB μ V] / [dB μ A/m]



磁场校正曲线 [dB μ A/m] / [dB μ V]

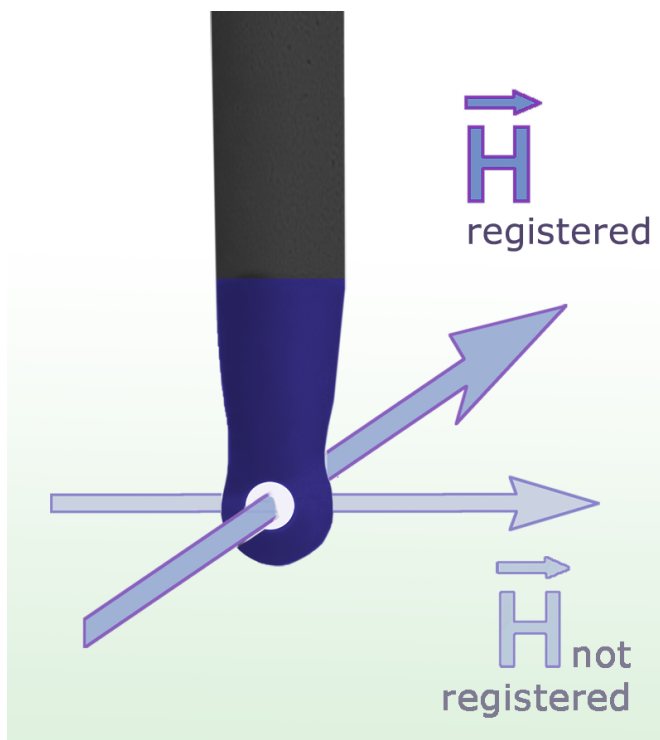
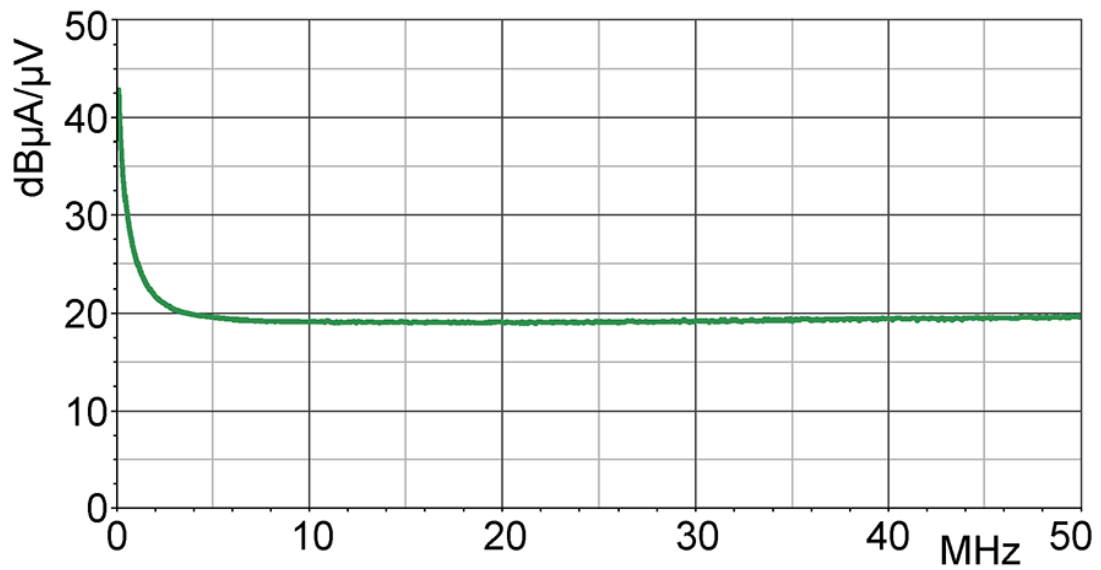


LF-R 3

磁场探头 (100KHz-50MHz)

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电流校正曲线 [dB μ A] / [dB μ V]



LF-R 3

磁场探头 (100KHz-50MHz)

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Probe head

